

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Kenichiro Kobayashi et al.

For : METHOD AND APPARATUS FOR DIRECT IMAGE PICK-UP OF
GRANULAR SPECK PATTERN GENERATED BY REFLECTING
LIGHT OF LASER BEAM

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Dear Sir:

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §1.97(b)

Pursuant to 37 CFR §§1.56 and 1.97(b), Applicants bring to the attention of the Examiner the documents listed on the attached Form PTO-1449. This Information Disclosure Statement is being filed within three months of the filing date of the above-referenced application.

Copies of the listed foreign patent documents are attached. As the Office has waived the requirement under 37 CFR §1.98(a)(2)(i) for submitting a copy of each cited U.S. patent and each U.S. patent application publication, copies of the listed U.S. patents and each U.S. patent application publication documents are not included with the submission of attached Form PTO 1449. Applicants respectfully request that the Examiner consider the listed documents and evidence that consideration by making appropriate notations on the attached form.

The following is a concise statement of relevance of the non-English language documents.

1. DE 197 39 679 A1 appears to show reflected light detected by a CCD detector.
2. French 2 701 762 appears to show a telescope (10) with a CCD camera (12).
3. DE 198 17 664 appears to show a focusing lens system for a laser (1) and a detector (8).
4. DE 199 09 235 A1 appears to show a camera lens system.
5. DE 196 20 419 A1 appears to show a laser (2) focused by lens (3) on target (1) with reflected light passing through lens (4) to sensors (5).

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This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitutes "prior art." If it should be determined that any of the listed documents do not constitute "prior art" under United States law, Applicants reserve the right to present to the Office the relevant facts and law regarding the appropriate status of such documents.

Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 16-2463.

Respectfully submitted,

KENICHIRO KOBAYASHI ET AL.

By: Price, Heneveld, Cooper,
DeWitt & Litton, LLP

12/16/03
Date

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FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE (Rev. 2-32) PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. KIK01 P-322A	SERIAL NO.
	APPLICANT(S) Kenichiro Kobayashi et al.	
	FILING DATE	GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPRO- PRIATE
		5	3	4	3	2	8	7	08/30/1994	Wilkins			
		4	6	2	1	0	6	3	11/04/1986	Wyatt et al.			
		4	7	9	4	3	8	4	12/27/1988	Jackson			
		5	6	3	3	7	1	4	05/27/1997	Nyyssonen			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLA- TION	
													Y	N
	DE	19	7	3	9	6	79	A1	10/1998	Germany				
		2	7	0	1	7	6	2	08/1994	France				
	DE	19	8	1	7	6	64	A1	11/1999	Germany				
	DE	19	9	0	9	2	35	A1	09/1999	Germany				
	DE	19	6	2	0	4	19	A1	11/1997	Germany				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER INITIAL		
		U.S. Patent Application Publication 2002/0080264, publication date June 27, 2002 entitled METHOD AND APPARATUS FOR DIRECT IMAGE PICK-UP OF GRANULAR SPECK PATTERN GENERATED BY REFLECTING LIGHT OF LASER BEAM

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	